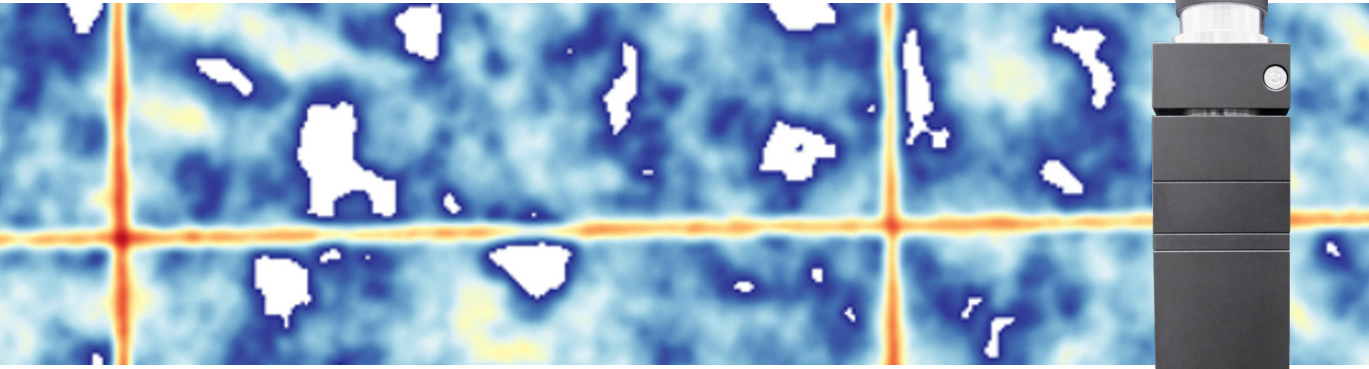


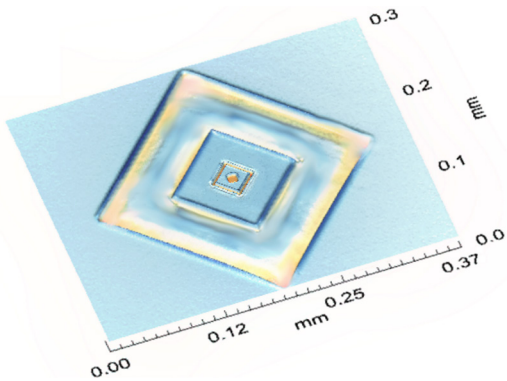
2D analysis by IR transmission images - IR Microscope -



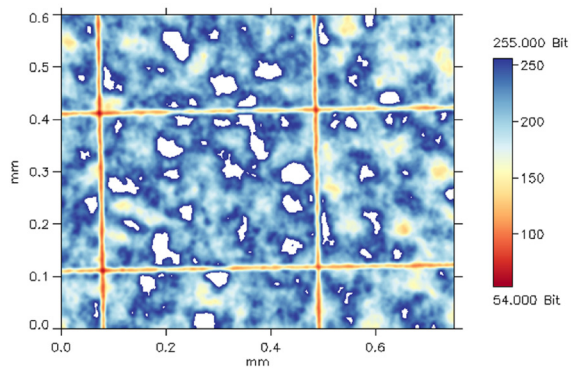
2D analysis of structures in NIR transparent materials

- > analysis of hidden structures in semiconductor and sapphire wafers, glasses and coatings
- > for laboratory, development, quality assurance and production
- > powerful industrial USB 3.0 camera with highly sensitive CMOS sensor
- > rolling shutter mode for extremely low-noise, high-contrast images
- > defective pixels are corrected by an automatic hotpixel correction
- > sample illumination by a manually-adjustable cold light source

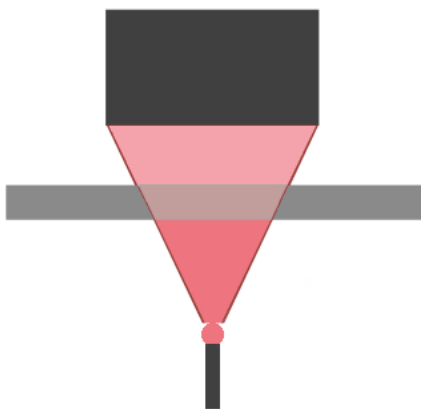
and much more...



Reference mark in 3D using IR camera



Stealth laser grooves in a bare Si wafer using IR microscope



Structure detection (IR)



MicroProf® DI – Flexible combination of inspection and metrology in one fully automated measurement tool